MOSFET – N-Channel, SUPERFET III, FRFET

650 V, 24 A, 150 m Ω

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power systems for miniaturization and higher efficiency. SUPERFET III FRFET MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- 700 V @ $T_J = 150^{\circ}C$
- Typ. R_{DS(on)} = 121 mΩ
- Ultra Low Gate Charge (Typ. Q_g = 43 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 400 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

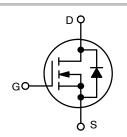
- Telecom / Server Power Supplies
- Industrial Power Supplies
- EV Charger
- UPS / Solar



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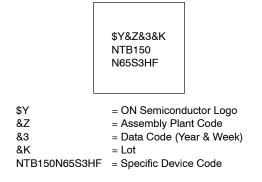
V _{DSS}	R _{DS(ON)} MAX	I _D MAX		
650 V	150 mΩ @ 10 V	24 A		



N-CHANNEL MOSFET



MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter	Value	Unit	
V _{DSS}	Drain to Source Voltage		650	V
V _{GSS}	Gate to Source Voltage	– DC	±30	V
		– AC (f > 1 Hz)	±30	
I _D	Drain Current	– Continuous (T _C = 25°C)	24	А
		– Continuous (T _C = 100°C)	15.2	
I _{DM}	Drain Current	- Pulsed (Note 1) 60		А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		275	mJ
I _{AS}	Avalanche Current (Note 2)		3.8	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		1.92	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		50	
PD	Power Dissipation	(T _C = 25°C)	192	W
		– Derate Above 25°C	1.54	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
ΤL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 3.8 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} \le 12 \text{ A}$, di/dt $\le 200 \text{ A}/\mu\text{s}$, $V_{DD} \le 400 \text{ V}$, starting $T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.65	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max., (Note 4)	40	

4. Device on 1 in² 2-oz copper pad on 1.5 x 1.5 in. board of FR-4 material.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Part Number Top Marking		Reel Size	Tape Width	Shipping [†]	
NTB150N65S3HF	NTB150N65S3HF	D ² PAK	330 mm	24 mm	800 / Tape & Reel	

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

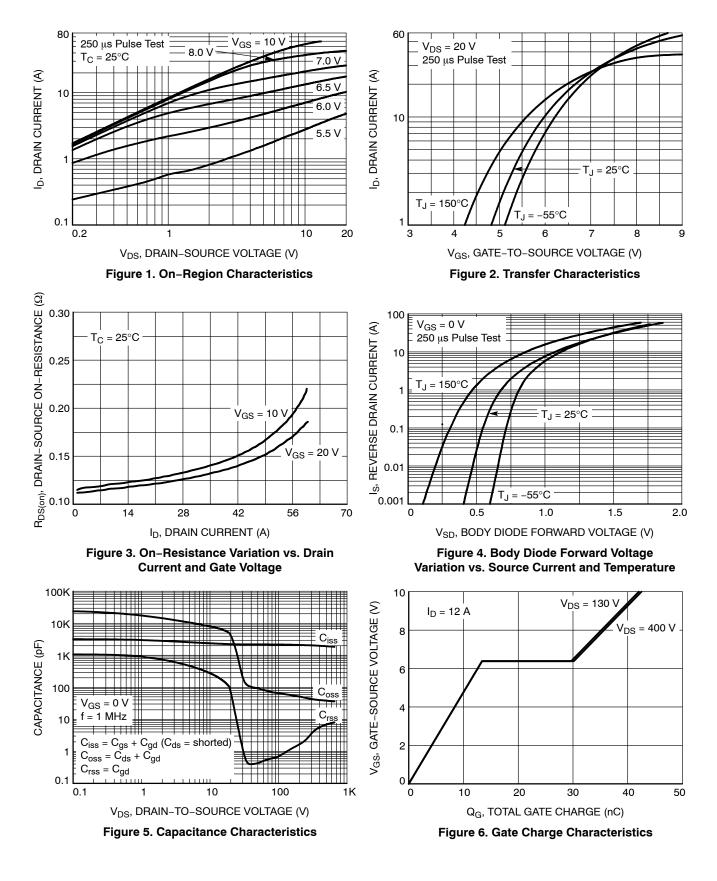
ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS	·			•	
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 1 mA, T_J = 25°C	650			V
		V_{GS} = 0 V, I_{D} = 1 mA, T_{J} = 150°C	700			V
$\Delta \text{BV}_{\text{DSS}}$ / $\Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 15 \text{ mA}, \text{ Referenced to } 25^{\circ}\text{C}$		0.62		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			10	μΑ
		V_{DS} = 520 V, T_{C} = 125°C		67		
I _{GSS}	Gate to Body Leakage Current	V_{GS} = ±30 V, V_{DS} = 0 V			±100	nA
ON CHARACTE	RISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 0.54$ mA	3.0		5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 12 A		121	150	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 12 A		14		S
OYNAMIC CHA	RACTERISTICS	·				
C _{iss}	Input Capacitance			1985		pF
C _{oss}	Output Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 1 MHz		40		pF
Coss(eff.)	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		400		pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		71		pF
Q _{g(tot)}	Total Gate Charge at 10 V			43		nC
Q _{gs}	Gate to Source Gate Charge	V _{DS} = 400 V, I _D = 12 A, V _{GS} = 10 V (Note 5)		13		nC
Q _{gd}	Gate to Drain "Miller" Charge	(1000)		17		nC
ESR	Equivalent Series Resistance	f = 1 MHz		5.0		Ω
WITCHING CH	IARACTERISTICS	·			•	•
t _{d(on)}	Turn-On Delay Time			21		ns
t _r	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 12 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$		19		ns
t _{d(off)}	Turn-Off Delay Time	R _g = 4.7 Ω (Note 5)		63		ns
t _f	Turn-Off Fall Time	1		14		ns
OURCE-DRAI	N DIODE CHARACTERISTICS	•	-		•	•
۱ _S	Maximum Continuous Source to Drain Diode Forward Current				24	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current				60	Α
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 12 A			1.3	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 12 A,	1	88		ns
Q _{rr}	Reverse Recovery Charge	$dI_{F}/dt = 100 \text{ A}/\mu \text{s}$	<u> </u>	306	1	nC

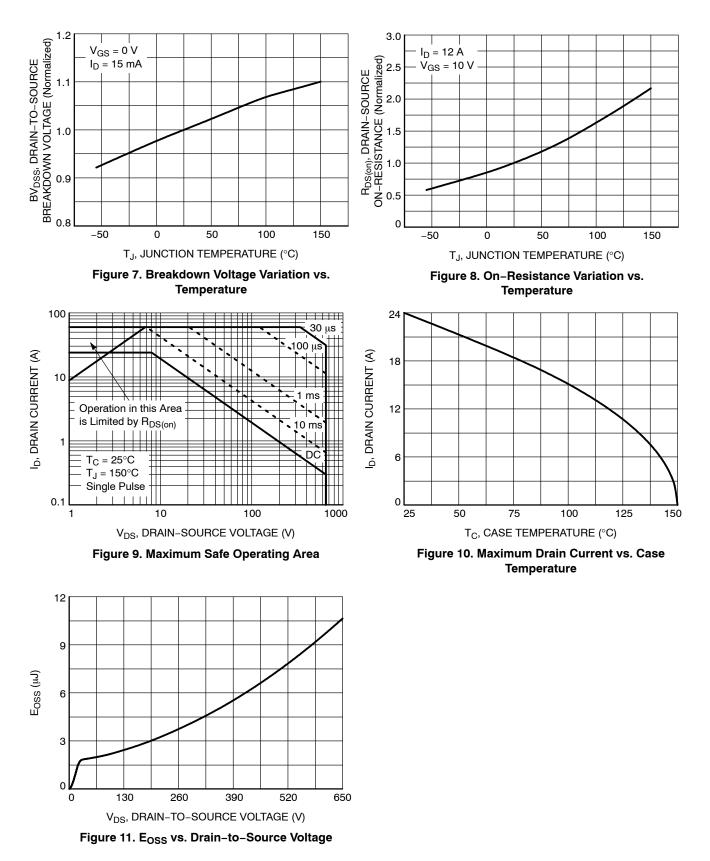
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

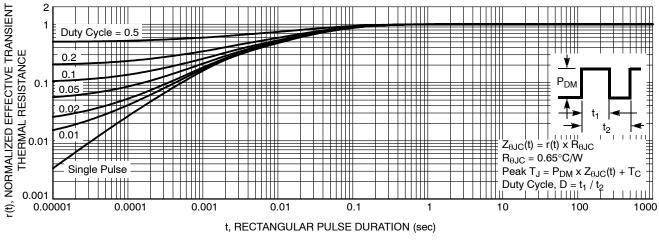
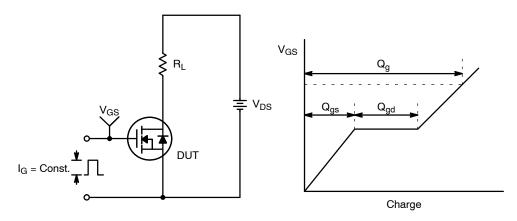


Figure 12. Transient Thermal Response Curve





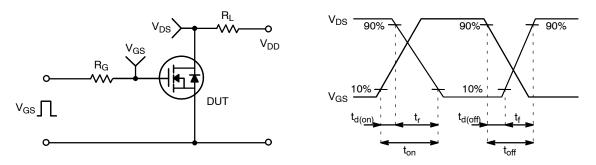
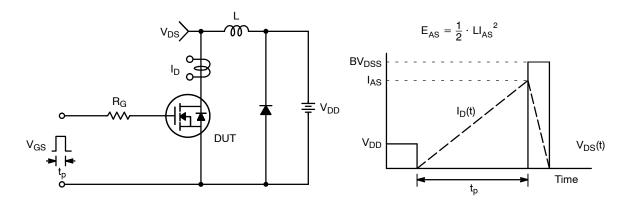


Figure 14. Resistive Switching Test Circuit & Waveforms





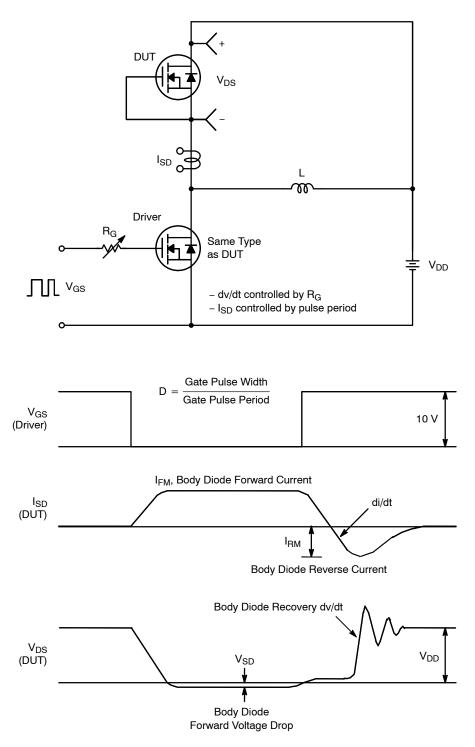
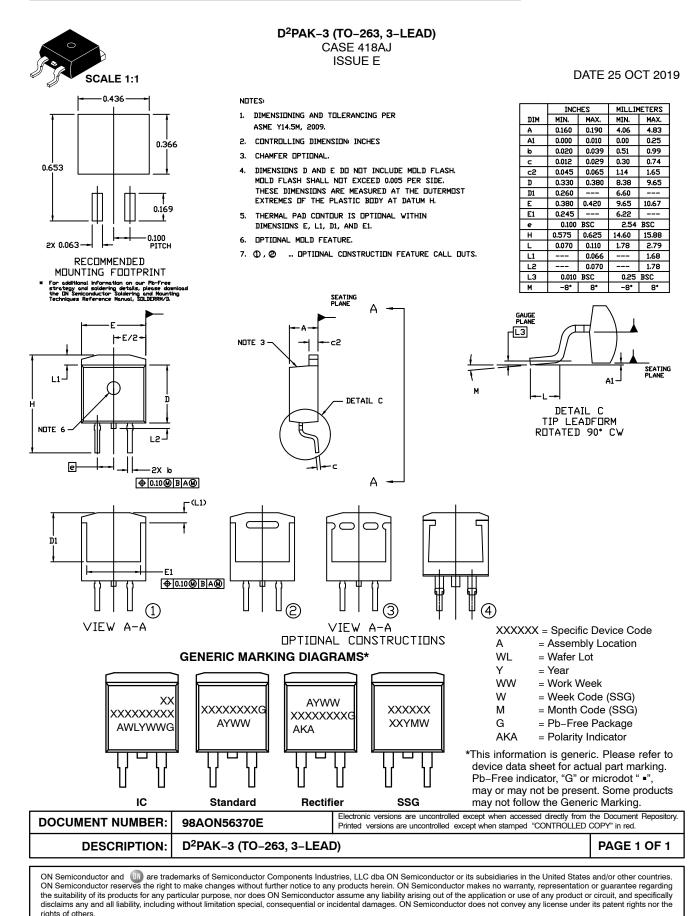


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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MECHANICAL CASE OUTLINE





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PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

TECHNICAL SUPPORT

ON Semiconductor Website: www.onsemi.com

Email Requests to: orderlit@onsemi.com

North American Technical Support: Voice Mail: 1 800–282–9855 Toll Free USA/Canada Phone: 011 421 33 790 2910 Europe, Middle East and Africa Technical Support: Phone: 00421 33 790 2910 For additional information, please contact your local Sales Representative